Se	earch Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination
09/583,959	HAMZY ET AL.
Examiner	Art Unit
Jungwon Chang	2154

	SEARCHED		
Class	Subclass	Date	Examiner
709	225	5/4/2005	JWC
709	219	5/4/2005	JWC
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
709	225	5/4/2005	JWC		
709	219	5/4/2005	JMC		
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SEARCH NOT (INCLUDING SEARCH S		)
	DATE	EXMR
East search NPL: Google ACM IEEE search report attached	5/4/2005	JWC
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